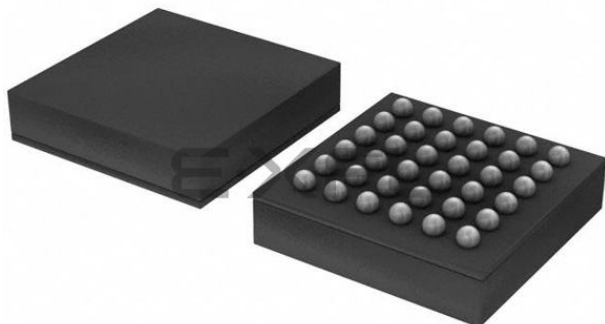




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Details

Product Status	Active
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	I ² C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, I ² S, LVD, POR, PWM, WDT
Number of I/O	26
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 7x16b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	36-UFBGA, WLCSP
Supplier Device Package	36-WLCSP (2.82x2.67)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mkl17z256cal4r

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Table 8. Power mode transition operating behaviors (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	• VLPS → RUN	—	7.5	8	μs	
	• STOP → RUN	—	7.5	8	μs	

1. Normal boot (FTFA_FOPT[LPBOOT]=11)

2.2.5 Power consumption operating behaviors

The maximum values stated in the following table represent characterized results equivalent to the mean plus three times the standard deviation (mean + 3 sigma).

NOTE

The while (1) test is executed with flash cache enabled.

NOTE

The data at 105 °C are for QFN, LQFP and MAPBGA packages only.

Table 9. Power consumption operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I _{DDA}	Analog supply current	—	—	See note	mA	1
I _{DD_RUNCO}	Running CoreMark in flash in compute operation mode—48M HIRC mode, 48 MHz core / 24 MHz flash, V _{DD} = 3.0 V - at 25 °C - at 105 °C	— —	5.76 6.04	6.40 6.68	mA	2
I _{DD_RUNCO}	Running While(1) loop in flash in compute operation mode—48M HIRC mode, 48 MHz core / 24 MHz flash, V _{DD} = 3.0 V - at 25 °C - at 105 °C	— —	3.21 3.49	3.85 4.13	mA	
I _{DD_RUN}	Run mode current—48M HIRC mode, running CoreMark in Flash all peripheral clock disable 48 MHz core/24 MHz flash, V _{DD} = 3.0 V - at 25 °C - at 105 °C	— —	6.45 6.75	7.09 7.39	mA	2
I _{DD_RUN}	Run mode current—48M HIRC mode, running CoreMark in flash all peripheral clock disable, 24 MHz core/12 MHz flash, V _{DD} = 3.0 V					2

Table continues on the next page...

Table 9. Power consumption operating behaviors

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
	- at 25 °C and below - at 50 °C - at 70 °C - at 85 °C - at 105 °C	—	0.18	0.28	μA	
		—	1.09	1.31		
		—	2.25	2.94		
		—	4.25	5.10		
		—	15.95	19.10		

1. The analog supply current is the sum of the active or disabled current for each of the analog modules on the device. See each module's specification for its supply current.
2. MCG_Lite configured for HIRC mode. CoreMark benchmark compiled using IAR 7.10 with optimization level high, optimized for balanced.
3. RTC uses external 32 kHz crystal as clock source, and the current includes ERCLK32K power consumption.

Table 10. Low power mode peripheral adders — typical value

Symbol	Description	Temperature (°C)						Unit
		-40	25	50	70	85	105	
I _{IRC8MHz}	8 MHz internal reference clock (IRC) adder. Measured by entering STOP or VLPS mode with 8 MHz IRC enabled, MCG_SC[FCRDIV]=000b, MCG_MC[LIRC_DIV2]=000b.	93	93	93	93	93	93	μA
I _{IRC2MHz}	2 MHz internal reference clock (IRC) adder. Measured by entering STOP mode with the 2 MHz IRC enabled, MCG_SC[FCRDIV]=000b, MCG_MC[LIRC_DIV2]=000b.	29	29	29	29	29	29	μA
I _{EREFSTEN4MHz}	External 4 MHz crystal clock adder. Measured by entering STOP or VLPS mode with the crystal enabled.	206	224	230	238	245	253	μA
I _{EREFSTEN32KHz}	External 32 kHz crystal clock adder by means of the OSC0_CR[EREFSTEN and EREFSTEN] bits. Measured by entering all modes with the crystal enabled. - VLLS1 - VLLS3 - LLS - VLPS - STOP							nA
		440	490	540	560	570	580	
		440	490	540	560	570	580	
		490	490	540	560	570	680	
		510	560	560	560	610	680	
		510	560	560	560	610	680	
I _{LPTMR}	LPTMR peripheral adder measured by placing the device in VLLS1 mode with LPTMR enabled using LPO.	30	30	30	85	100	200	

Table continues on the next page...

Table 10. Low power mode peripheral adders — typical value (continued)

Symbol	Description	Temperature (°C)						Unit
		-40	25	50	70	85	105	
								nA
I _{CMP}	CMP peripheral adder measured by placing the device in VLLS1 mode with CMP enabled using the 6-bit DAC and a single external input for compare. Includes 6-bit DAC power consumption.	22	22	22	22	22	22	μA
I _{UART}	UART peripheral adder measured by placing the device in STOP or VLPS mode with selected clock source waiting for RX data at 115200 baud rate. Includes selected clock source power consumption. • IRC8M (8 MHz internal reference clock) • IRC2M (2 MHz internal reference clock)	114	114	114	114	114	114	μA
		34	34	34	34	34	34	
I _{TPM}	TPM peripheral adder measured by placing the device in STOP or VLPS mode with selected clock source configured for output compare generating 100 Hz clock signal. No load is placed on the I/O generating the clock signal. Includes selected clock source and I/O switching currents. • IRC8M (8 MHz internal reference clock) • IRC2M (2 MHz internal reference clock)	147	147	147	147	147	147	μA
		42	42	42	42	42	42	
I _{BG}	Bandgap adder when BGEN bit is set and device is placed in VLPx or VLLSx mode.	45	45	45	45	45	45	μA
I _{ADC}	ADC peripheral adder combining the measured values at V _{DD} and V _{DDA} by placing the device in STOP or VLPS mode. ADC is configured for low power mode using the internal clock and continuous conversions.	330	330	330	330	330	330	μA

2.2.5.1 Diagram: Typical IDD_RUN operating behavior

The following data was measured under these conditions:

- MCG-Lite in HIRC for run mode, and LIRC for VLPR mode
- No GPIOs toggled
- Code execution from flash
- For the ALLOFF curve, all peripheral clocks are disabled except FTFA

of *Electromagnetic Emissions, 150 kHz to 1 GHz Part 2: Measurement of Radiated Emissions—TEM Cell and Wideband TEM Cell Method*. Measurements were made while the microcontroller was running basic application code. The reported emission level is the value of the maximum measured emission, rounded up to the next whole number, from among the measured orientations in each frequency range.

2. $V_{DD} = 3.3\text{ V}$, $T_A = 25\text{ °C}$, $f_{OSC} = \text{IRC48M}$, $f_{SYS} = 48\text{ MHz}$, $f_{BUS} = 24\text{ MHz}$
3. Specified according to Annex D of IEC Standard 61967-2, *Measurement of Radiated Emissions—TEM Cell and Wideband TEM Cell Method*

2.2.7 Designing with radiated emissions in mind

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions:

1. Go to www.freescale.com.
2. Perform a keyword search for “EMC design.”

2.2.8 Capacitance attributes

Table 12. Capacitance attributes

Symbol	Description	Min.	Max.	Unit
C_{IN}	Input capacitance	—	7	pF

2.3 Switching specifications

2.3.1 Device clock specifications

Table 13. Device clock specifications

Symbol	Description	Min.	Max.	Unit
Normal run mode				
f_{SYS}	System and core clock ¹	—	48	MHz
f_{BUS}	Bus clock ¹	—	24	MHz
f_{FLASH}	Flash clock ¹	—	24	MHz
f_{LPTMR}	LPTMR clock	—	24	MHz
VLPR and VLPS modes ²				
f_{SYS}	System and core clock	—	4	MHz
f_{BUS}	Bus clock	—	1	MHz
f_{FLASH}	Flash clock	—	1	MHz
f_{LPTMR}	LPTMR clock ³	—	24	MHz

Table continues on the next page...

1. Maximum T_A can be exceeded only if the user ensures that T_J does not exceed the maximum. The simplest method to determine T_J is: $T_J = T_A + R_{\theta JA} \times \text{chip power dissipation}$.

Table 16. Thermal operating requirements for other packages

Symbol	Description	Min.	Max.	Unit	Notes
T_J	Die junction temperature	−40	125	°C	
T_A	Ambient temperature	−40	105	°C	1

1. Maximum T_A can be exceeded only if the user ensures that T_J does not exceed the maximum. The simplest method to determine T_J is: $T_J = T_A + R_{\theta JA} \times \text{chip power dissipation}$.

2.4.2 Thermal attributes

Table 17. Thermal attributes

Board type	Symbol	Description	48 QFN	32 QFN	64 LQFP	64 MAPB GA	36 WLCS P	Unit	Notes
Single-layer (1S)	$R_{\theta JA}$	Thermal resistance, junction to ambient (natural convection)	86	101	70	50.3	77.6	°C/W	1
Four-layer (2s2p)	$R_{\theta JA}$	Thermal resistance, junction to ambient (natural convection)	29	33	51	42.9	38.9	°C/W	
Single-layer (1S)	$R_{\theta JMA}$	Thermal resistance, junction to ambient (200 ft./min. air speed)	71	84	58	41.4	69.6	°C/W	
Four-layer (2s2p)	$R_{\theta JMA}$	Thermal resistance, junction to ambient (200 ft./min. air speed)	24	28	45	38.0	35.6	°C/W	
—	$R_{\theta JB}$	Thermal resistance, junction to board	12	13	33	39.6	34.8	°C/W	2
—	$R_{\theta JC}$	Thermal resistance, junction to case	1.7	1.7	20	27.3	0.37	°C/W	3
—	Ψ_{JT}	Thermal characterization parameter, junction to package top outside center (natural convection)	2	3	4	0.4	0.2	°C/W	4
—	Ψ_{JB}	Thermal characterization parameter, junction to package bottom (natural convection)	-	-	-	12.6	-	°C/W	5

1. Determined according to JEDEC Standard JESD51-2, *Integrated Circuits Thermal Test Method Environmental Conditions—Natural Convection (Still Air)*, or EIA/JEDEC Standard JESD51-6, *Integrated Circuit Thermal Test Method Environmental Conditions—Forced Convection (Moving Air)*.
2. Determined according to JEDEC Standard JESD51-8, *Integrated Circuit Thermal Test Method Environmental Conditions—Junction-to-Board*.

Table 19. IRC48M specification (continued)

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
T_j	Period jitter (RMS)	—	35	150	ps	—
T_{su}	Startup time	—	2	3	μs	—

1. The maximum value represents characterized results equivalent to mean plus or minus three times the standard deviation (mean $\pm 3\sigma$).

Table 20. IRC8M/2M specification

Symbol	Description	Min.	Typ.	Max.	Unit	Notes
I_{DD_2M}	Supply current in 2 MHz mode	—	14	17	μA	—
I_{DD_8M}	Supply current in 8 MHz mode	—	30	35	μA	—
f_{IRC_2M}	Output frequency	—	2	—	MHz	—
f_{IRC_8M}	Output frequency	—	8	—	MHz	—
$f_{IRC_T_2M}$	Output frequency range (trimmed)	—	—	± 3	% f_{IRC}	—
$f_{IRC_T_8M}$	Output frequency range (trimmed)	—	—	± 3	% f_{IRC}	—
T_{su_2M}	Startup time	—	—	12.5	μs	—
T_{su_8M}	Startup time	—	—	12.5	μs	—

3.6.1.1 16-bit ADC operating conditions

Table 27. 16-bit ADC operating conditions

Symbol	Description	Conditions	Min.	Typ. ¹	Max.	Unit	Notes
V_{DDA}	Supply voltage	Absolute	1.71	—	3.6	V	—
ΔV_{DDA}	Supply voltage	Delta to V_{DD} ($V_{DD} - V_{DDA}$)	-100	0	+100	mV	2
ΔV_{SSA}	Ground voltage	Delta to V_{SS} ($V_{SS} - V_{SSA}$)	-100	0	+100	mV	2
V_{REFH}	ADC reference voltage high		1.13	V_{DDA}	V_{DDA}	V	3
V_{REFL}	ADC reference voltage low		V_{SSA}	V_{SSA}	V_{SSA}	V	3
V_{ADIN}	Input voltage	16-bit differential mode - All other modes	V_{REFL} V_{REFL}	— —	$31/32 \times V_{REFH}$ V_{REFH}	V	—
C_{ADIN}	Input capacitance	16-bit mode 8-bit / 10-bit / 12-bit modes	— —	8 4	10 5	pF	—
R_{ADIN}	Input series resistance		—	2	5	k Ω	—
R_{AS}	Analog source resistance (external)	13-bit / 12-bit modes $f_{ADCK} < 4$ MHz	—	—	5	k Ω	4
f_{ADCK}	ADC conversion clock frequency	$\leq$ 13-bit mode	1.0	—	24	MHz	5
f_{ADCK}	ADC conversion clock frequency	16-bit mode	2.0	—	12.0	MHz	5
C_{rate}	ADC conversion rate	$\leq$ 13-bit modes No ADC hardware averaging Continuous conversions enabled, subsequent conversion time	20.000	—	1200	ksps	6
C_{rate}	ADC conversion rate	16-bit mode No ADC hardware averaging Continuous conversions enabled, subsequent conversion time	37.037	—	461.467	ksps	6

1. Typical values assume $V_{DDA} = 3.0$ V, Temp = 25 °C, $f_{ADCK} = 1.0$ MHz, unless otherwise stated. Typical values are for reference only, and are not tested in production.
2. DC potential difference.
3. V_{REFH} can act as V_{REF_OUT} when V_{REFV1} module is enabled.
4. This resistance is external to MCU. To achieve the best results, the analog source resistance must be kept as low as possible. The results in this data sheet were derived from a system that had $< 8 \Omega$ analog source resistance. The R_{AS}/C_{AS} time constant should be kept to < 1 ns.
5. To use the maximum ADC conversion clock frequency, CFG2[ADHSC] must be set and CFG1[ADLPC] must be clear.
6. For guidelines and examples of conversion rate calculation, download the [ADC calculator tool](#).

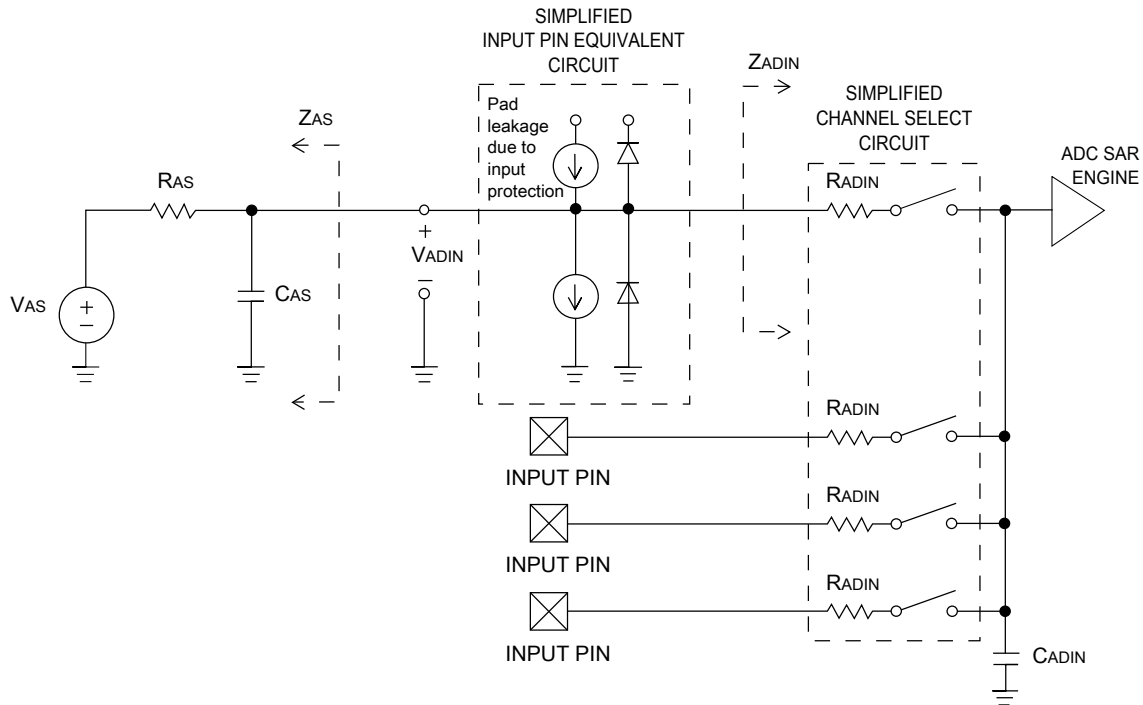


Figure 7. ADC input impedance equivalency diagram

3.6.1.2 16-bit ADC electrical characteristics

Table 28. 16-bit ADC characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$)

Symbol	Description	Conditions ¹	Min.	Typ. ²	Max.	Unit	Notes
I_{DDA_ADC}	Supply current		0.215	—	1.7	mA	3
f_{ADACK}	ADC asynchronous clock source	• ADLPC = 1, ADHSC = 0 • ADLPC = 1, ADHSC = 1 • ADLPC = 0, ADHSC = 0 • ADLPC = 0, ADHSC = 1	1.2 2.4 3.0 4.4	2.4 4.0 5.2 6.2	3.9 6.1 7.3 9.5	MHz MHz MHz MHz	$t_{ADACK} = 1/f_{ADACK}$
	Sample Time	See Reference Manual chapter for sample times					
TUE	Total unadjusted error	• 12-bit modes • <12-bit modes	— —	± 4 ± 1.4	± 6.8 ± 2.1	LSB ⁴	5
DNL	Differential non-linearity	• 12-bit modes • <12-bit modes	— —	± 0.7 ± 0.2	-1.1 to $+1.9$ -0.3 to 0.5	LSB ⁴	5
INL	Integral non-linearity	• 12-bit modes	—	± 1.0	-2.7 to $+1.9$	LSB ⁴	5

Table continues on the next page...

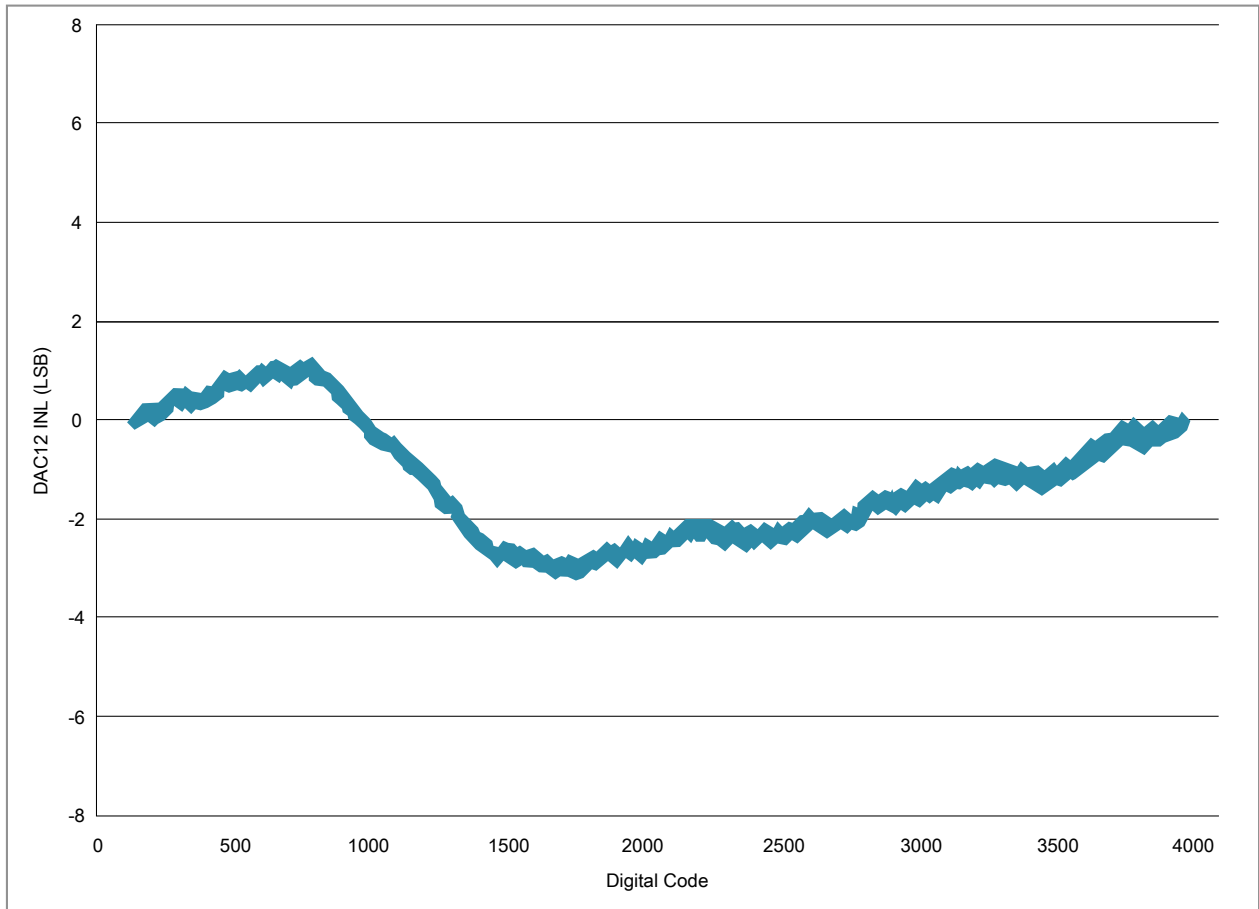


Figure 12. Typical INL error vs. digital code

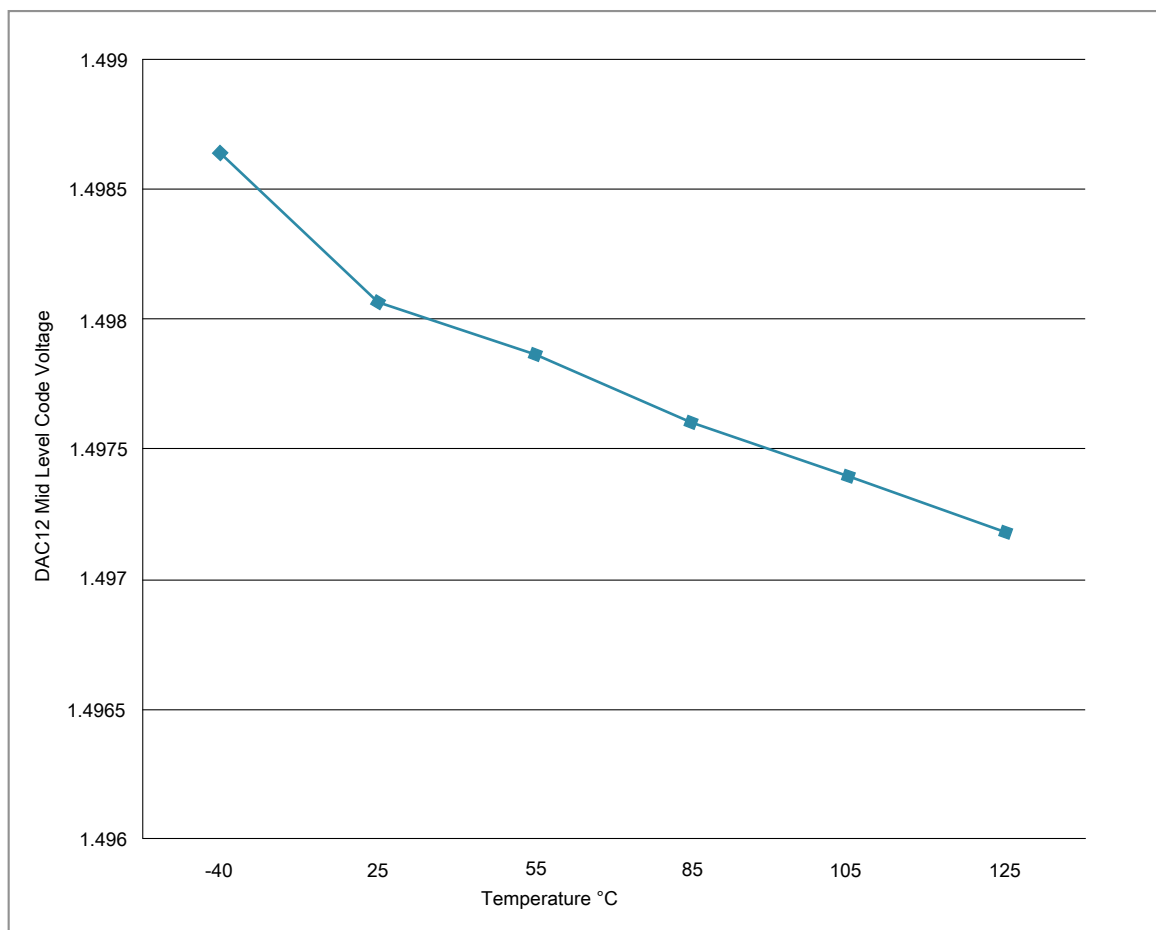


Figure 13. Offset at half scale vs. temperature

3.7 Timers

See [General switching specifications](#).

3.8 Communication interfaces

Table 39. SPI slave mode timing on slew rate enabled pads

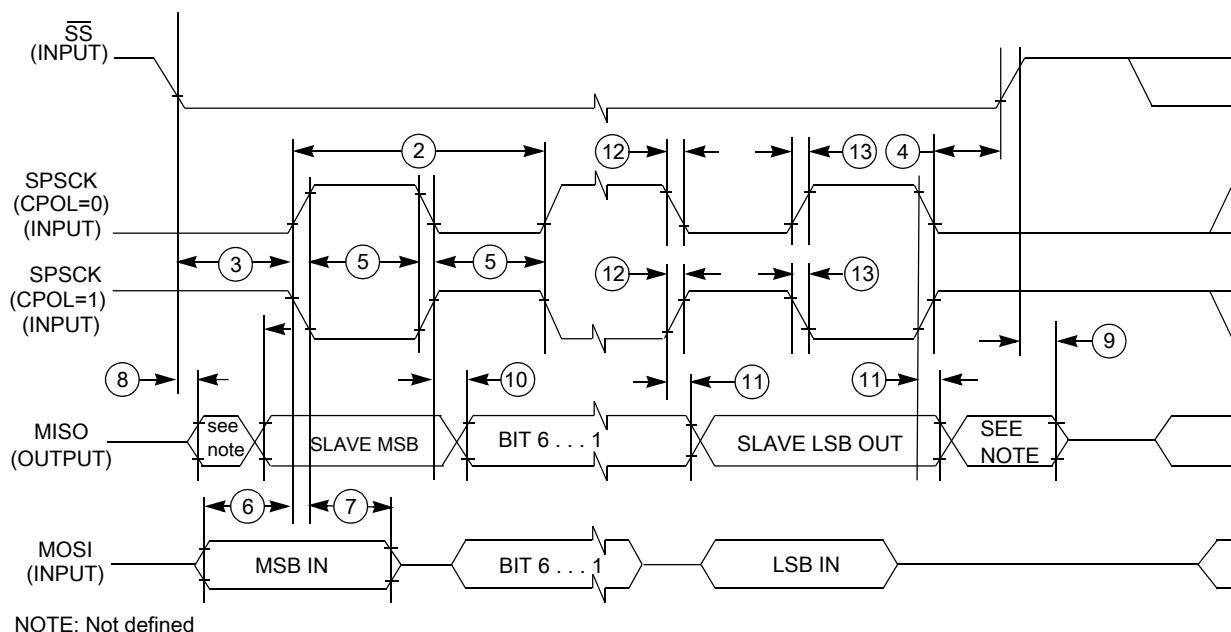
Num.	Symbol	Description	Min.	Max.	Unit	Note
1	f_{op}	Frequency of operation	0	$f_{periph}/4$	Hz	1
2	t_{SPSCK}	SPSCK period	$4 \times t_{periph}$	—	ns	2
3	t_{Lead}	Enable lead time	1	—	t_{periph}	—
4	t_{Lag}	Enable lag time	1	—	t_{periph}	—
5	t_{WSPSCK}	Clock (SPSCK) high or low time	$t_{periph} - 30$	—	ns	—
6	t_{SU}	Data setup time (inputs)	2	—	ns	—
7	t_{HI}	Data hold time (inputs)	7	—	ns	—
8	t_a	Slave access time	—	t_{periph}	ns	3
9	t_{dis}	Slave MISO disable time	—	t_{periph}	ns	4
10	t_v	Data valid (after SPSCK edge)	—	122	ns	—
11	t_{HO}	Data hold time (outputs)	0	—	ns	—
12	t_{RI}	Rise time input	—	$t_{periph} - 25$	ns	—
	t_{FI}	Fall time input				
13	t_{RO}	Rise time output	—	36	ns	—
	t_{FO}	Fall time output				

1. For SPI0 f_{periph} is the bus clock (f_{BUS}). For SPI1 f_{periph} is the system clock (f_{SYS}).

2. $t_{periph} = 1/f_{periph}$

3. Time to data active from high-impedance state

4. Hold time to high-impedance state

**Figure 16. SPI slave mode timing (CPHA = 0)**

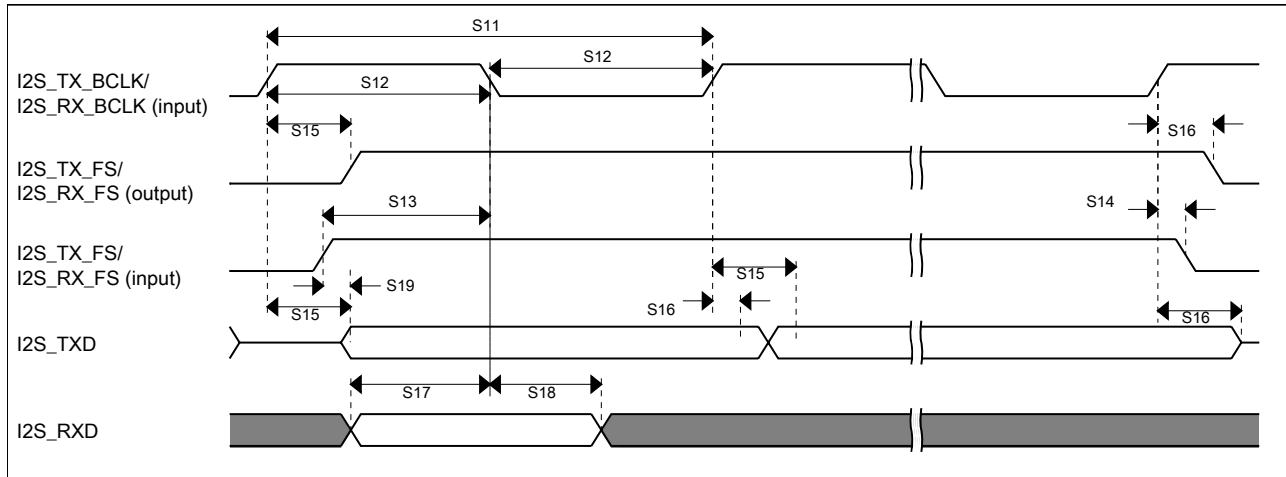


Figure 20. I2S/SAI timing — slave modes

3.8.4.2 VLPR, VLPW, and VLPS mode performance over the full operating voltage range

This section provides the operating performance over the full operating voltage for the device in VLPR, VLPW, and VLPS modes.

Table 44. I2S/SAI master mode timing in VLPR, VLPW, and VLPS modes (full voltage range)

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S1	I2S_MCLK cycle time	62.5	—	ns
S2	I2S_MCLK pulse width high/low	45%	55%	MCLK period
S3	I2S_TX_BCLK/I2S_RX_BCLK cycle time (output)	250	—	ns
S4	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output valid	—	45	ns
S6	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output invalid	0	—	ns
S7	I2S_TX_BCLK to I2S_TXD valid	—	45	ns
S8	I2S_TX_BCLK to I2S_TXD invalid	0	—	ns
S9	I2S_RXD/I2S_RX_FS input setup before I2S_RX_BCLK		—	ns
S10	I2S_RXD/I2S_RX_FS input hold after I2S_RX_BCLK	0	—	ns

5 Pinouts and Packaging

5.1 KL17 signal multiplexing and pin assignments

The following table shows the signals available on each pin and the locations of these pins on the devices supported by this document. The Port Control Module is responsible for selecting which ALT functionality is available on each pin.

NOTE

VREFH can act as VREF_OUT when VREFV1 module is enabled.

NOTE

It is prohibited to set VREFEN in 32 QFN and 36 WLCSP pin packages because 1.2 V on-chip voltage is not available in these packages.

64 MAP BGA	64 LQFP	48 QFN	36 WLC SP	32 QFN	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7
A1	1	—	—	1	PTE0	DISABLED		PTE0/ CLKOUT32 K	SPI1_MISO	LPUART1_ TX	RTC_ CLKOUT	CMP0_OUT	I2C1_SDA	
B1	2	—	—	2	PTE1	DISABLED		PTE1	SPI1_MOSI	LPUART1_ RX		SPI1_MISO	I2C1_SCL	
—	3	1	—	—	VDD	VDD	VDD							
C4	4	2	—	—	VSS	VSS	VSS							
E1	5	3	—	3	PTE16	ADC0_DP1/ ADC0_SE1	ADC0_DP1/ ADC0_SE1	PTE16	SPI0_PCS0	UART2_TX	TPM_ CLKIN0		FXIO0_D0	
D1	6	4	—	4	PTE17	ADC0_DM1/ ADC0_SE5a	ADC0_DM1/ ADC0_SE5a	PTE17	SPI0_SCK	UART2_RX	TPM_ CLKIN1	LPTMR0_ ALT3	FXIO0_D1	
E2	7	5	—	5	PTE18	ADC0_DP2/ ADC0_SE2	ADC0_DP2/ ADC0_SE2	PTE18	SPI0_MOSI		I2C0_SDA	SPI0_MISO	FXIO0_D2	
D2	8	6	—	6	PTE19	ADC0_DM2/ ADC0_SE6a	ADC0_DM2/ ADC0_SE6a	PTE19	SPI0_MISO		I2C0_SCL	SPI0_MOSI	FXIO0_D3	
G1	9	7	—	—	PTE20	ADC0_DP0/ ADC0_SE0	ADC0_DP0/ ADC0_SE0	PTE20		TPM1_CH0	LPUART0_ TX		FXIO0_D4	
F1	10	8	—	—	PTE21	ADC0_DM0/ ADC0_SE4a	ADC0_DM0/ ADC0_SE4a	PTE21		TPM1_CH1	LPUART0_ RX		FXIO0_D5	
G2	11	—	—	—	PTE22	ADC0_DP3/ ADC0_SE3	ADC0_DP3/ ADC0_SE3	PTE22		TPM2_CH0	UART2_TX		FXIO0_D6	
F2	12	—	—	—	PTE23	ADC0_DM3/ ADC0_SE7a	ADC0_DM3/ ADC0_SE7a	PTE23		TPM2_CH1	UART2_RX		FXIO0_D7	

Pinouts and Packaging

64 MAP BGA	64 LQFP	48 QFN	36 WLC SP	32 QFN	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7
F4	13	9	E6	7	VDDA	VDDA	VDDA							
G4	14	10	E6	—	VREFH	VREFH	VREFH							
G3	15	11	F6	—	VREFL	VREFL	VREFL							
F3	16	12	F6	8	VSSA	VSSA	VSSA							
H1	17	13	—	—	PTE29	CMP0_IN5/ ADC0_SE4b	CMP0_IN5/ ADC0_SE4b	PTE29		TPM0_CH2	TPM_ CLKIN0			
H2	18	14	E5	9	PTE30	DAC0_OUT/ ADC0_ SE23/ CMP0_IN4	DAC0_OUT/ ADC0_ SE23/ CMP0_IN4	PTE30		TPM0_CH3	TPM_ CLKIN1	LPUART1_ TX	LPTMR0_ ALT1	
H3	19	—	—	—	PTE31	DISABLED		PTE31		TPM0_CH4				
H4	20	15	—	—	PTE24	DISABLED		PTE24		TPM0_CH0		I2C0_SCL		
H5	21	16	—	—	PTE25	DISABLED		PTE25		TPM0_CH1		I2C0_SDA		
D3	22	17	F5	10	PTA0	SWD_CLK		PTA0		TPM0_CH5				SWD_CLK
D4	23	18	E4	11	PTA1	DISABLED		PTA1	LPUART0_ RX	TPM2_CH0				
E5	24	19	D4	12	PTA2	DISABLED		PTA2	LPUART0_ TX	TPM2_CH1				
D5	25	20	F4	13	PTA3	SWD_DIO		PTA3	I2C1_SCL	TPM0_CH0				SWD_DIO
G5	26	21	F3	14	PTA4	NMI_b		PTA4	I2C1_SDA	TPM0_CH1				NMI_b
F5	27	—	—	—	PTA5	DISABLED		PTA5		TPM0_CH2			I2S0_TX_ BCLK	
H6	28	—	—	—	PTA12	DISABLED		PTA12		TPM1_CH0			I2S0_TXD0	
G6	29	—	—	—	PTA13	DISABLED		PTA13		TPM1_CH1			I2S0_TX_ FS	
—	—	—	E3	—	PTA14	DISABLED		PTA14	SPI0_PCS0	LPUART0_ TX			I2S0_RX_ BCLK	I2S0_TXD0
—	—	—	D3	—	PTA15	DISABLED		PTA15	SPI0_SCK	LPUART0_ RX			I2S0_RXD0	
—	—	—	C3	—	PTA16	DISABLED		PTA16	SPI0_MOSI			SPI0_MISO	I2S0_RX_ FS	I2S0_RXD0
—	—	—	D2	—	PTA17	DISABLED		PTA17	SPI0_MISO			SPI0_MOSI	I2S0_MCLK	
G7	30	22	E2	15	VDD	VDD	VDD							
H7	31	23	F2	16	VSS	VSS	VSS							
H8	32	24	F1	17	PTA18	EXTAL0	EXTAL0	PTA18		LPUART1_ RX	TPM_ CLKIN0			
G8	33	25	E1	18	PTA19	XTAL0	XTAL0	PTA19		LPUART1_ TX	TPM_ CLKIN1		LPTMR0_ ALT1	
F8	34	26	D1	19	PTA20	RESET_b		PTA20						RESET_b
F7	35	27	C2	20	PTB0/ LLWU_P5	ADC0_SE8	ADC0_SE8	PTB0/ LLWU_P5	I2C0_SCL	TPM1_CH0				
F6	36	28	C1	21	PTB1	ADC0_SE9	ADC0_SE9	PTB1	I2C0_SDA	TPM1_CH1				
E7	37	29	—	—	PTB2	ADC0_SE12	ADC0_SE12	PTB2	I2C0_SCL	TPM2_CH0				

64 MAP BGA	64 LQFP	48 QFN	36 WLC SP	32 QFN	Pin Name	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7
A2	64	48	B6	32	PTD7	DISABLED		PTD7	SPI1_MISO	LPUART0_TX		SPI1_MOSI	FXIO0_D7	
C5	—	—	C5	—	Reserved	Reserved	Reserved							
—	—	—	C6	—	Reserved	Reserved	Reserved							
—	—	—	D5	—	Reserved	Reserved	Reserved							
—	—	—	D6	—	Reserved	Reserved	Reserved							

5.2 KL17 Family Pinouts

Figure below shows the 32 QFN pinouts:

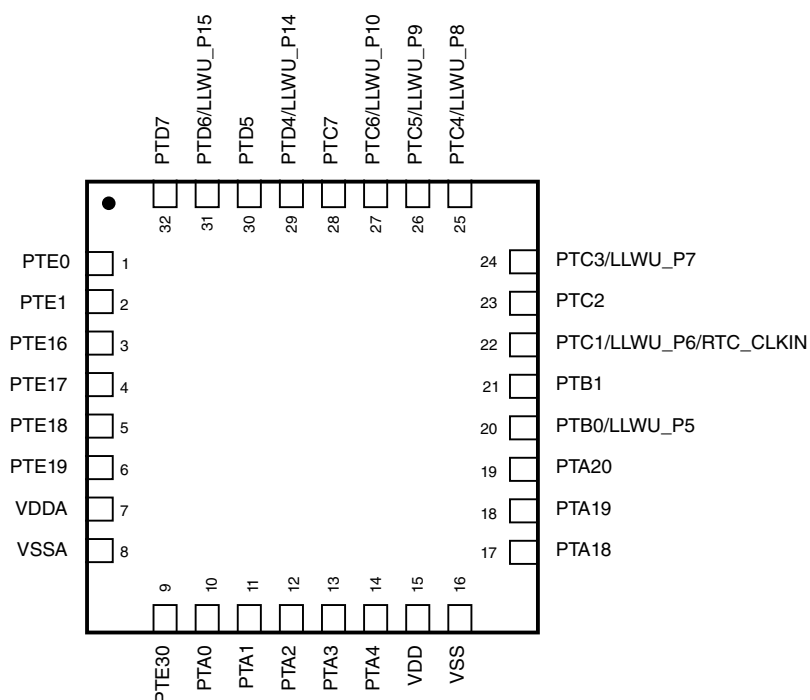


Figure 23. 32 QFN Pinout diagram

Figure below shows the 36 WLCSP pinouts:

Pinouts and Packaging

	1	2	3	4	5	6	
A	PTC3	PTC4	PTC5	PTC7	PTD4	PTD6	A
B	PTC1	PTC2	VDD	PTC6	PTD5	PTD7	B
C	PTB1	PTB0	PTA16	VSS	Reserved	Reserved	C
D	PTA20	PTA17	PTA15	PTA2	Reserved	Reserved	D
E	PTA19	VDD	PTA14	PTA1	PTE30	VDDA/ VREFH	E
F	PTA18	VSS	PTA4	PTA3	PTA0	VSSA/ VREFL	F
	1	2	3	4	5	6	

Figure 24. 36 WLCSP Pinout diagram

Figure below shows the 48 QFN pinouts:

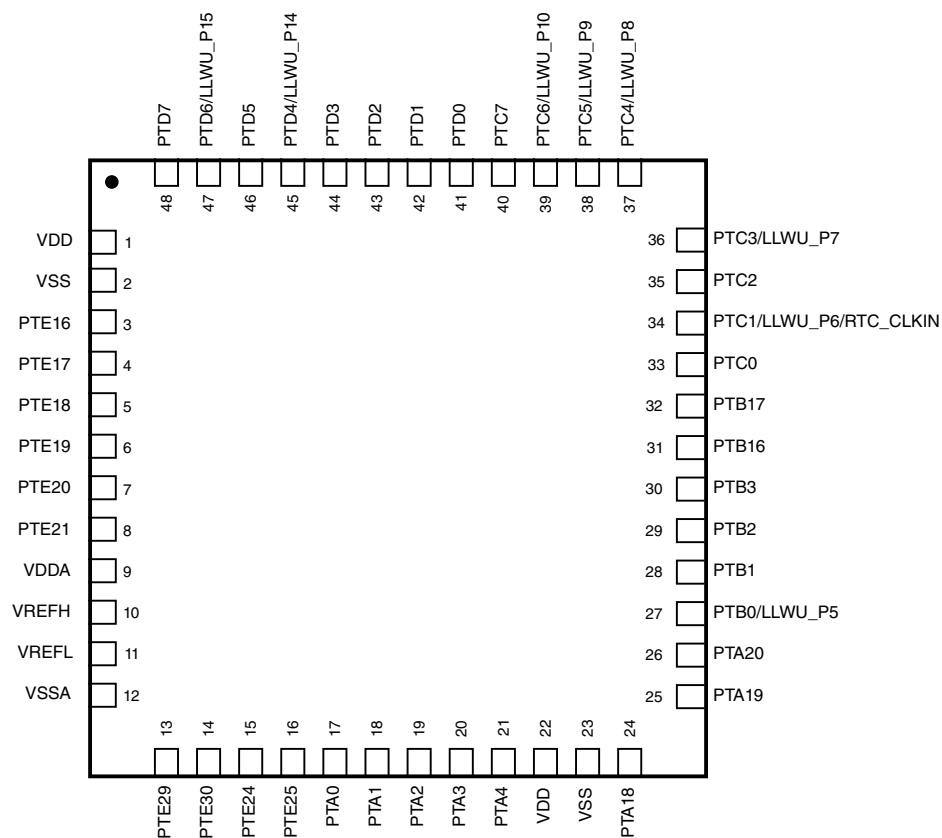


Figure 25. 48 QFN Pinout diagram

Figure below shows the 64 MAPBGA pinouts:

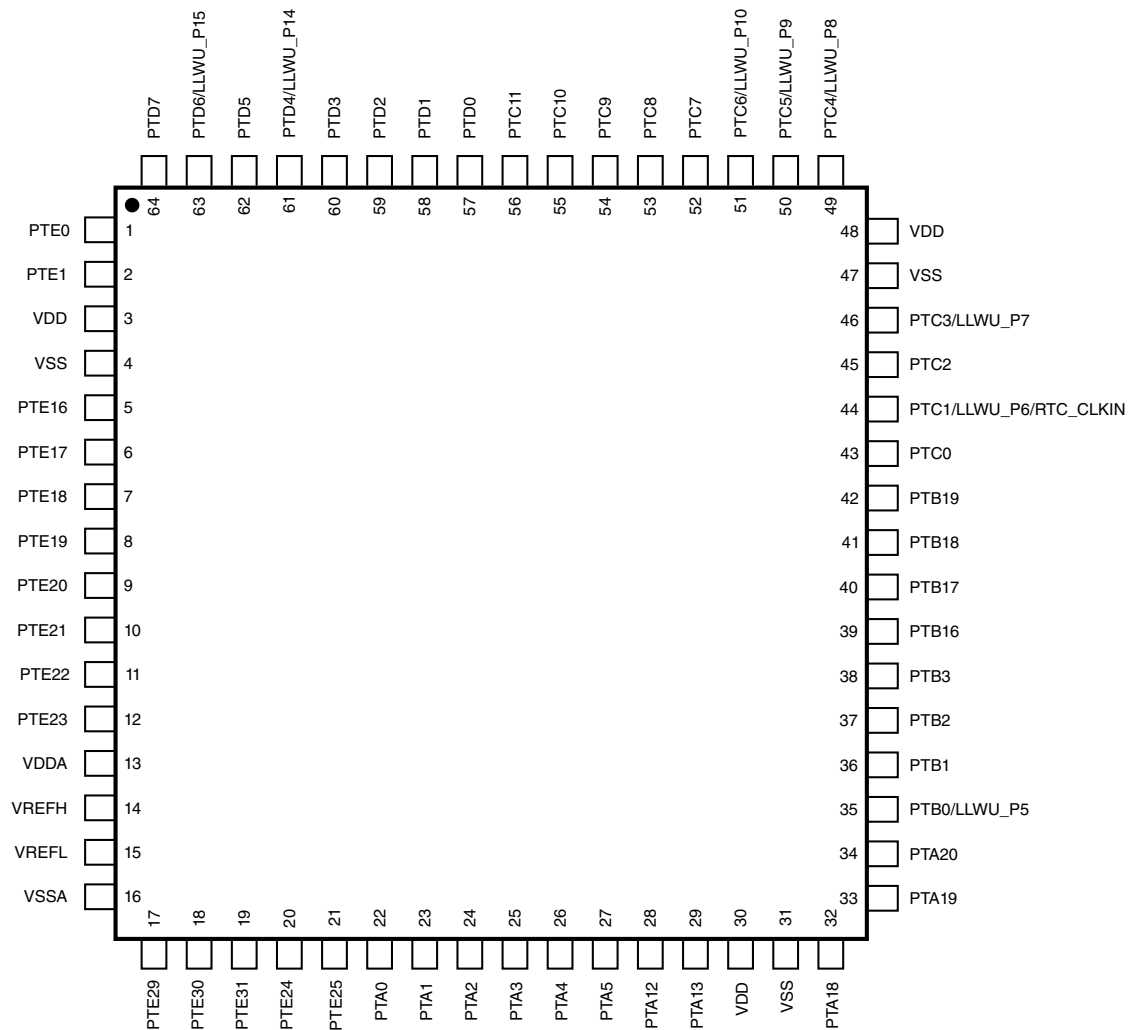


Figure 27. 64 LQFP Pinout diagram

5.3 Recommended connection for unused analog and digital pins

Table 46 shows the recommended connections for analog interface pins if those analog interfaces are not used in the customer's application

7.1 Description

Part numbers for the chip have fields that identify the specific part. You can use the values of these fields to determine the specific part you have received.

7.2 Format

Part numbers for this device have the following format:

Q KL## A FFF R T PP CC N

7.3 Fields

This table lists the possible values for each field in the part number (not all combinations are valid):

Table 47. Part number fields descriptions

Field	Description	Values
Q	Qualification status	- M = Fully qualified, general market flow - P = Prequalification
KL##	Kinetis family	KL17
A	Key attribute	Z = Cortex-M0+
FFF	Program flash memory size	128 = 128 KB 256 = 256 KB
R	Silicon revision	(Blank) = Main - A = Revision after main
T	Temperature range (°C)	- V = -40 to 105 - C = -40 to 85
PP	Package identifier	- FM = 32 QFN (5 mm x 5 mm) - AL = 36 WLCSP (2.8 mm x 2.7 mm) - FT = 48 QFN (7 mm x 7 mm) - LH = 64 LQFP (10 mm x 10 mm) - MP = 64 MAPBGA (5 mm x 5 mm)
CC	Maximum CPU frequency (MHz)	4 = 48 MHz
N	Packaging type	R = Tape and reel

7.4 Example

This is an example part number: